

74ABT2952 Octal Registered Transceiver

General Description

The 'ABT2952 is an octal registered transceiver. Two 8-bit back to back registers store data flowing in both directions between two bidirectional buses. Separate clock, clock enable and TRI-STATE® output enable signals are provided for each register. The output pins are guaranteed to source 32 mA (24 mA mil.) and to sink 64 mA (48 mA mil).

Features

- Separate clock, clock enable and TRI-STATE output enable provided for each register
- A and B output sink capability of 64 mA source capability of 32 mA

- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

Commercial	Package Number	Package Description
74ABT2952CSC (Note 1)	M24B	24-Lead (0.300" Wide) Molded Small Outline, JEDEC
74ABT2952CMSA (Note 1)	MSA24	24-Lead Molded Shrink Small Outline, EIAJ Type II
74ABT2952CMTC (Notes 1, 2)	MTC24	24-Lead Molded Thin Shrink Small Outline, JEDEC

Note 1: Devices also available in 13" reel. Use suffix = SCX, MSAX and MTCX.

Note 2: Contact factory for package availability.

Connection Diagram

TL/F/10969-3

Pin Descriptions

Pin Names	Description
A ₀ -A ₇	A-Register Inputs/B-Register
	TRI-STATE Outputs
B ₀ -B ₇	B-Register Inputs/A-Register
	TRI-STATE Outputs
ŌĒĀ	Output Enable A-Register
CPA	A-Register Clock
CEA	A-Register Clock Enable
OEB	Output Enable B-Register
CPB	B-Register Clock
CEB	B-Register Clock Enable

TRI-STATE® is a registered trademark of National Semiconductor Corporation

Pin Descriptions (Continued)

Output Control

ŌĒ	Internal Q	Output 'ABT2952	Function
Н	Х	Z	Disable Outputs
L L	L H	L H	Enable Outputs

 $\begin{array}{ll} H = HIGH \ Voltage \ Level \\ L = LOW \ Voltage \ Level \\ X = Immaterial \end{array}$

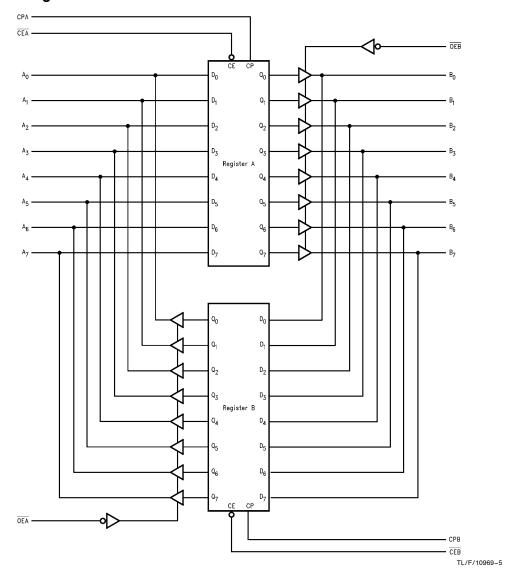
Z = HIGH Impedance

— = LOW-to-HIGH Transition
NC = No Change

Register Function Table (Applies to A or B Register)

	Inputs		Internal	Function	
D	СР	CE	Q	runction	
Х	Х	Н	NC	Hold Data	
L	\	L	L	Load Data	
Н		L	Н		

Block Diagram



Absolute Maximum Ratings (Note 1)

-65°C to +150°C Storage Temperature -55°C to +125°C Ambient Temperature under Bias

Junction Temperature under Bias

Plastic -55° C to $+150^{\circ}$ C

V_{CC} Pin Potential to

Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disable or Power-Off State -0.5V to +5.5V-0.5V to V $_{\rm CC}$ in the HIGH State

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Current Applied to Output in LOW State (Max)

twice the rated I_{OL} (mA)

DC Latchup Source Current $-500\ \text{mA}$ 10V

Over Voltage Latchup (I/O)

Recommended Operating Conditions

Free Air Ambient Temperature

-40°C to +85°C Commercial

Supply Voltage

Commercial $+\,4.5V$ to $+\,5.5V$

Minimum Input Edge Rate $(\Delta V/\Delta t)$ Data Input 50 mV/ns Enable Input 20 mV/ns Clock Input 100 mV/ns

DC Electrical Characteristics

Symbol	Parameter		ABT2952		Units	Vcc	Conditions	
Syllibol	Parameter	Min	Тур	Max	Units	VCC	Conditions	
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal	
V _{IL}	Input LOW Voltage			8.0	V		Recognized LOW Signal	
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	$I_{IN} = -18 \text{ mA (Non I/O Pins)}$	
V _{OH}	Output HIGH Voltage 74AB 74AB						$\begin{split} I_{OH} &= -3 \text{ mA } (A_n, B_n) \\ I_{OH} &= -32 \text{ mA } (A_n, B_n) \end{split}$	
V _{OL}	Output LOW Voltage 74AB	Т		0.55	V	Min	$I_{OL} = 64 \text{ mA } (A_n, B_n)$	
V _{ID}	Input Leakage Test	4.75			V	0.0	$I_{\text{ID}} = 1.9 \ \mu\text{A}$ (Non-I/O Pins) All Other Pins Grounded	
IIH	Input HIGH Current			5	μΑ	Max	$V_{\text{IN}} = 2.7 \text{V (Non-I/O Pins) (Note 2)}$ $V_{\text{IN}} = V_{\text{CC}}$ (Non-I/O Pins)	
I _{BVI}	Input HIGH Current Breakdown Test			7	μΑ	Max	V _{IN} = 7.0V (Non-I/O Pins)	
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			100	μΑ	Max	$V_{IN} = 5.5V (A_n, B_n)$	
I _{IL}	Input LOW Current			-5	μΑ	Max	$V_{IN} = 0.5V$ (Non-I/O Pins) (Note 2) $V_{IN} = 0.0V$ (Non-I/O Pins)	
I _{IH} + I _{OZH}	Output Leakage Current			50	μΑ	0V-5.5V	$\frac{V_{OUT} = 2.7V (A_n, B_n)}{OEA \text{ or } OEB = 2.0V}$	
I _{IL} + I _{OZL}	Output Leakage Current			-50	μΑ	0V-5.5V	$\frac{V_{OUT} = 0.5V (A_n, B_n)}{OEA \text{ or } OEB = 2.0V}$	
Ios	Output Short-Circuit Current	-100		-275	mA	Max	$V_{OUT} = 0V(A_n, B_n)$	
I _{CEX}	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n)$	
I _{ZZ}	Bus Drainage Test			100	μΑ	0.0V	$V_{OUT} = 5.5V (A_n, B_n);$ All Others GND	
Icch	Power Supply Current			250	μΑ	Max	All Outputs HIGH	
ICCL	Power Supply Current			30	mA	Max	All Outputs LOW	
Iccz	Power Supply Current			50	μΑ	Max	Outputs TRI-STATE; All Others GND	
ГССТ	Additional I _{CC} /Input			2.5	mA	Max	$V_{I} = V_{CC} - 2.1V$; All Others at V_{CC} or GND	
Iccd	Dynamic I _{CC} No Loa (Note 2)	d		0.18	mA/MHz	Max	Outputs Open OEA or OEB = GND, Non-I/O = GND or V _{CC} One Bit toggling, 50% duty cycle (Note 1)	

Note 1: For 8-bit toggling, $I_{CCD} < 1.4 \text{ mA/MHz}.$

Note 2: Guaranteed, but not tested.

DC Electrical Characteristics (SOIC package) (Continued)

Symbol	Parameter	Min	Тур	Max	Units	v _{cc}	
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}		0.6	0.8	٧	5.0	T _A = 25°C (Note 1)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	-1.2	-1.0		٧	5.0	T _A = 25°C (Note 1)
V _{OHV}	Minimum High Level Dynamic Output Voltage	2.5	3.0		٧	5.0	T _A = 25°C (Note 3)
V _{IHD}	Minimum High Level Dynamic Input Voltage	2.0	1.7		V	5.0	T _A = 25°C (Note 2)
V _{ILD}	Maximum Low Level Dynamic Input Voltage		1.2	8.0	٧	5.0	T _A = 25°C (Note 2)

 $\textbf{Note 1:} \ \text{Max number of outputs defined as (n).} \ n-1 \ \text{data inputs are driven 0V to 3V}. \ \text{One output at Low. Guaranteed, but not tested.}$

Note 2: Max number of data inputs (n) switching. n-1 inputs switching 0V to 3V. Input-under-test switching: 3V to the shold (V_{ILD}) , 0V to threshold (V_{IHD}) . Guaranteed, but not tested.

Note 3: Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

AC Electrical Characteristics

Symbol	Parameter		$ \begin{array}{c} \textbf{74ABT} \\ \textbf{T_A} = +25^{\circ}\textbf{C} \\ \textbf{V_{CC}} = +5.0\textbf{V} \\ \textbf{C_L} = 50\textbf{pF} \end{array} $		$ \begin{array}{lll} T_{\text{A}} = +25^{\circ}\text{C} & T_{\text{A}} = -40^{\circ}\text{C to} + 85^{\circ}\text{C} \\ V_{\text{CC}} = +5.0\text{V} & V_{\text{CC}} = 4.5\text{V to} 5.5\text{V} \\ \end{array} $		$V_{CC} = +5.0V$		$T_A = -40^{\circ}\text{C to} + 85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to} 5.5\text{V}$		Units
		Min	Тур	Max	Min	Max					
f _{max}	Max Clock Frequency	200			200		MHz				
t _{PLH} t _{PHL}	Propagation Delay CPA or CPB to A _n or B _n	1.5 1.5	3.4 3.6	5.3 5.3	1.5 1.5	5.3 5.3	ns				
t _{PZH} t _{PZL}	Output Enable Time OEA or OEB to A _n or B _n	1.5 1.5	3.2 3.5	5.5 5.5	1.5 1.5	5.5 5.5	ns				
t _{PHZ} t _{PLZ}	Output Disable Time OEA or OEB to An or Bn	1.5 1.5	3.6 3.2	6.0 6.0	1.5 1.5	6.0 6.0	ns				

AC Operating Requirements

		74	ABT	74	ABT	
Symbol	$ \begin{array}{c c} \textbf{T}_{\textbf{A}} = +25^{\circ}\textbf{C} \\ \textbf{V}_{\textbf{CC}} = +5.0\textbf{V} \\ \textbf{C}_{\textbf{L}} = \textbf{50}\textbf{pF} \end{array} $		+ 5.0V	$ extsf{T}_{ extsf{A}} = -40^{\circ} extsf{C} ext{ to } +85^{\circ} extsf{C} \ extsf{V}_{ extsf{CC}} = 4.5 extsf{V} ext{ to } 5.5 extsf{V} \ extsf{C}_{ extsf{L}} = 50 ext{ pF} \$		Units
		Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW A _n or B _n to CPA or CPB	2.5 2.5		2.5 2.5		ns
t _h (H) t _h (L)	Hold Time, HIGH or LOW A _n or B _n to CPA or CPB	1.5 1.5		1.5 1.5		ns
t _S (H)	Setup Time, HIGH or LOW CEA or CEB to CPA or CPB	2.5 2.5		2.5 2.5		ns
t _h (H)	Hold Time, HIGH or LOW CEA or CEB to CPA or CPB	1.5 1.5		1.5 1.5		ns
t _w (H) t _w (L)	Pulse Width, HIGH or LOW CPA or CPB	3.0 3.0		3.0 3.0		ns

Extended AC Electrical Characteristics

Symbol	Parameter	$74ABT$ $T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_L = 50 \text{ pF}$ $8 \text{ Outputs Switching}$ (Note 4)		$\begin{aligned} & 74\text{ABT} \\ & \textbf{T}_{\textbf{A}} = -40^{\circ}\text{C to } +85^{\circ}\text{C} \\ & \textbf{V}_{\textbf{CC}} = 4.5\text{V to } 5.5\text{V} \\ & \textbf{C}_{\textbf{L}} = 250~\text{pF} \\ & (\text{Note 5}) \end{aligned}$		74ABT T _A = -40°C to +85°C V _{CC} = 4.5V to 5.5V C _L = 250 pF 8 Outputs Switching (Note 6)		Units
		Min	Max	Min	Max	Min	Max	
t _{PLH}	Progagation Delay	1.5	6.0	2.0	8.0	2.5	10.5	ns
t _{PHL}	CPA or CPB to A _n or B _n	1.5	6.0	2.0	8.0	2.5	10.5	113
t _{PZH}	Output Enable Time	1.5	6.0	2.0	8.0	2.5	11.5	
t _{PZL}	\overline{OEA} or \overline{OEB} to A_n or B_n	1.5	6.0	2.0	8.0	2.5	11.5	ns
t _{PHZ}	Output Disable Time OEA or OEB to An or Bn	1.5 1.5	6.0 6.0	(Note 7)		7) (Note 7)		ns

Note 4: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 5: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in pice of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 6: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 7: The TRI-STATE delays are dominated by the RC network (500 Ω , 250 pF) on the output and has been excluded from the datasheet.

Skew

		74ABT	74ABT	
Symbol	Parameter	$\begin{aligned} \mathbf{T_A} &= -40^{\circ}\text{C to } + 85^{\circ}\text{C} \\ \mathbf{V_{CC}} &= 4.5\text{V} - 5.5\text{V} \\ \mathbf{C_L} &= 50 \text{ pF} \\ 8 \text{ Outputs Switching} \\ \text{(Note 3)} \end{aligned}$	$\begin{aligned} \textbf{T}_{\textbf{A}} &= -40^{\circ}\textbf{C} \text{ to } +85^{\circ}\textbf{C} \\ \textbf{V}_{\textbf{CC}} &= 4.5\textbf{V} -5.5\textbf{V} \\ \textbf{C}_{\textbf{L}} &= 250 \text{ pF} \\ \textbf{8} \text{ Outputs Switching} \\ \textbf{(Note 4)} \end{aligned}$	Units
		Max	Max	
t _{OSHL} (Note 1)	Pin to Pin Skew HL Transitions	1.0	1.5	ns
t _{OSLH} (Note 1)	Pin to Pin Skew LH Transitions	1.0	2.0	ns
t _{PS} (Note 5)	Duty Cycle LH-HL Skew	2.0	4.5	ns
t _{OST} (Note 1)	Pin to Pin Skew LH/HL Transitions	2.1	4.5	ns
t _{PV} (Note 2)	Device to Device Skew LH/HL Transitions	2.5	5.0	ns

Note 1: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW (toSHL), LOW to HIGH (toSLH), or any combination switching LOW to HIGH and/or HIGH to LOW (toST). This specification is guaranteed but not tested.

Note 2: Propagation delay variation for a given set of conditions (i.e., temperature and V_{CC}) from device to device. This specification is guaranteed but not tested.

Note 3: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 4: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

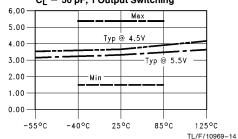
Note 5: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

Capacitance

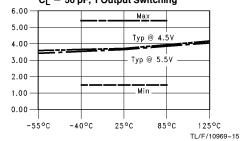
Symbol	Symbol Parameter		Units	Conditions T _A = 25°C	
C _{IN}	Input Capacitance	5	pF	V _{CC} = 0V (Non I/O Pins)	
C _{I/O} (Note 1)	Output Capacitance	11	pF	$V_{CC} = 5.0V (A_n, B_n)$	

Note 1: $C_{I/O}$ is measured at frequency f = 1 MHz, per MIL-STD-883B, Method 3012.

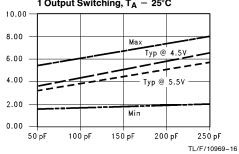
t_{PLH} vs Temperature (T_A) C_L = 50 pF, 1 Output Switching

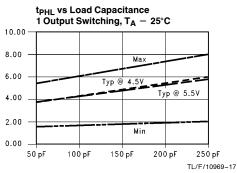


 t_{PHL} vs Temperature (T_A) $C_L = 50$ pF, 1 Output Switching

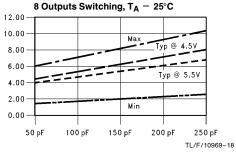


 t_{PLH} vs Load Capacitance 1 Output Switching, $T_A=25^{\circ}C$

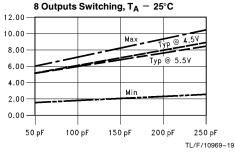




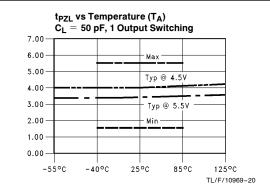
t_{PLH} vs Load Capacitance

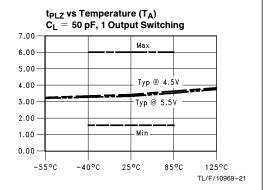


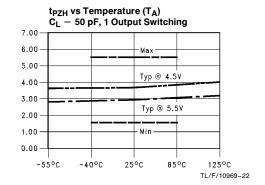
t_{PHL} vs Load Capacitance

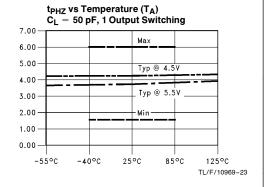


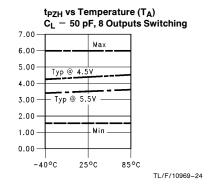
Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

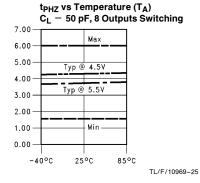




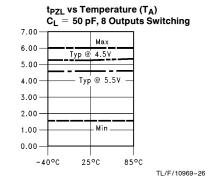


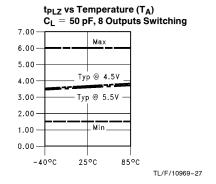


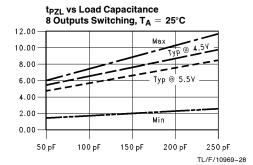


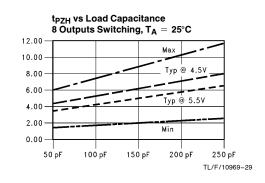


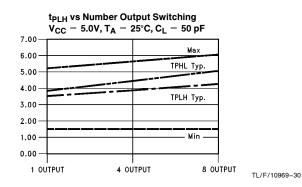
Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.





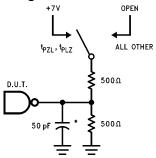






Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

AC Loading



TL/F/10969-6

*Includes jig and probe capacitance

FIGURE 1. Standard AC Test Load

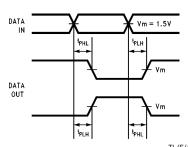


FIGURE 3. Propagation Delay Waveforms for Inverting and Non-Inveting Functions

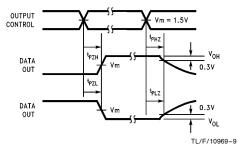


FIGURE 5. TRI-STATE Output HIGH and LOW Enable and Disable Times

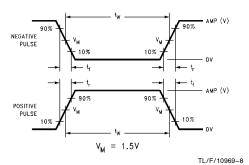


FIGURE 2a. Test Input Signal Levels

Amplitude	itude Rep. Rate		t _r	t _f	
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns	

FIGURE 2b. Input Signal Requirements

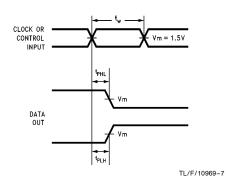


FIGURE 4. Propagation Delay, Pulse Width Waveforms

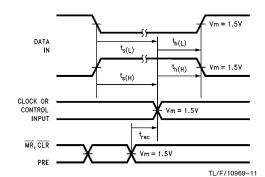
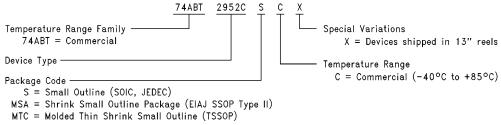


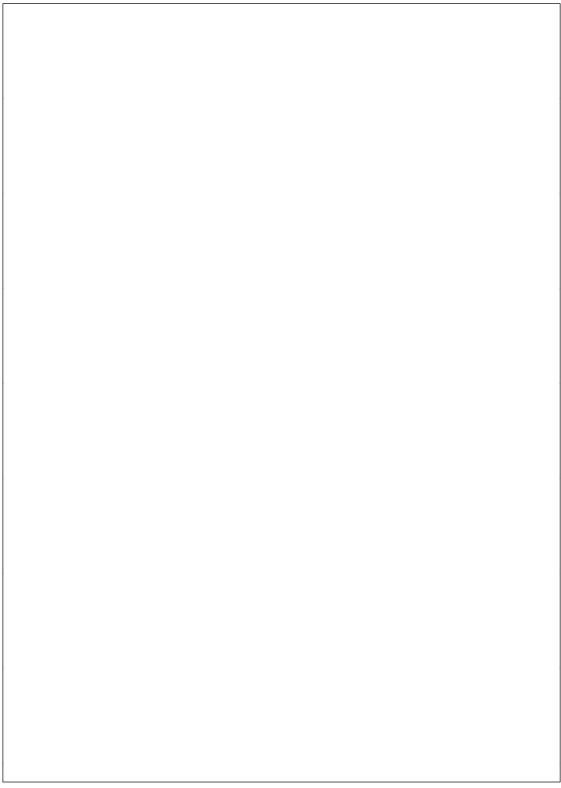
FIGURE 6. Setup Time, Hold Time and Recovery Time Waveforms

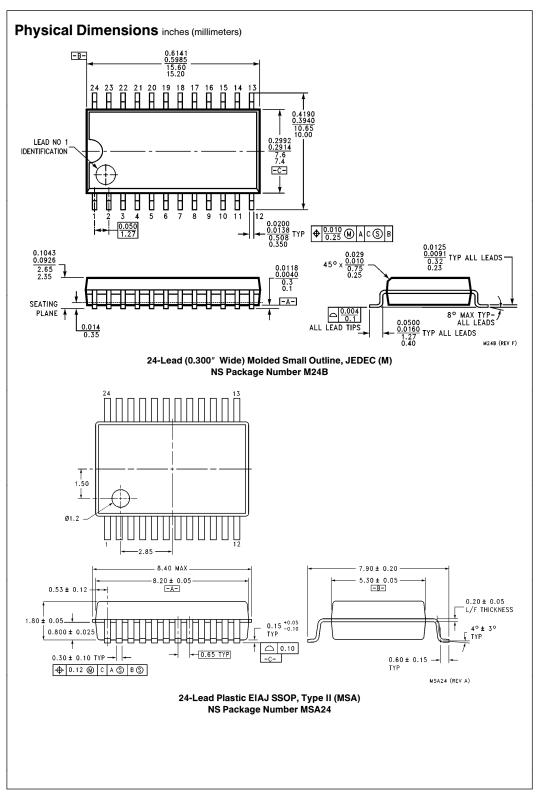
Ordering Information

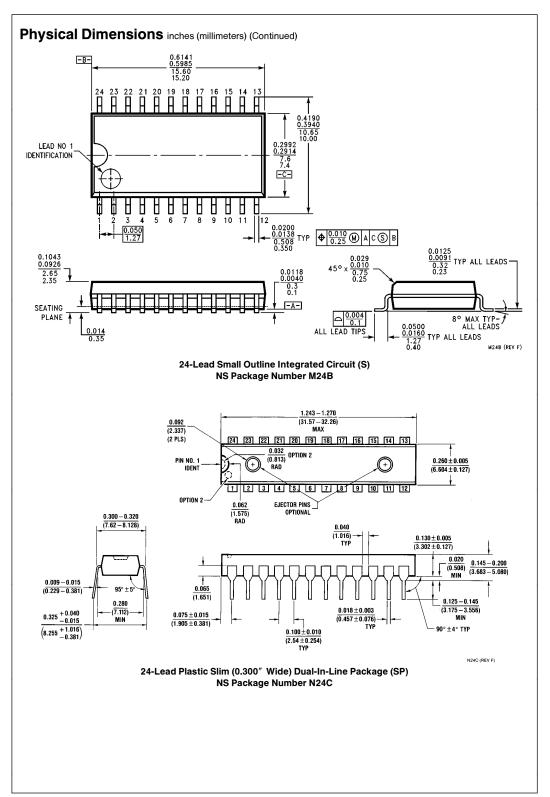
The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

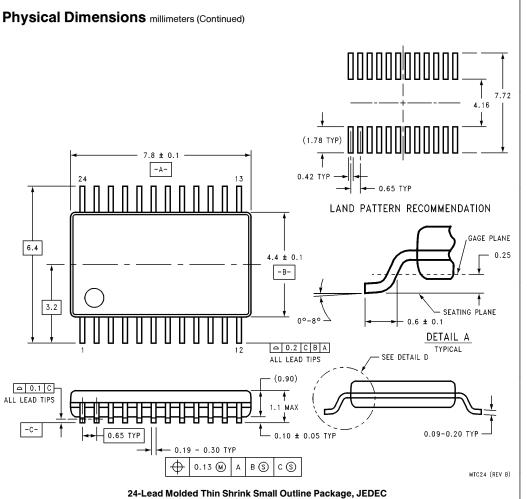


TL/F/10969-31









NS Package Number MTC24

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- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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